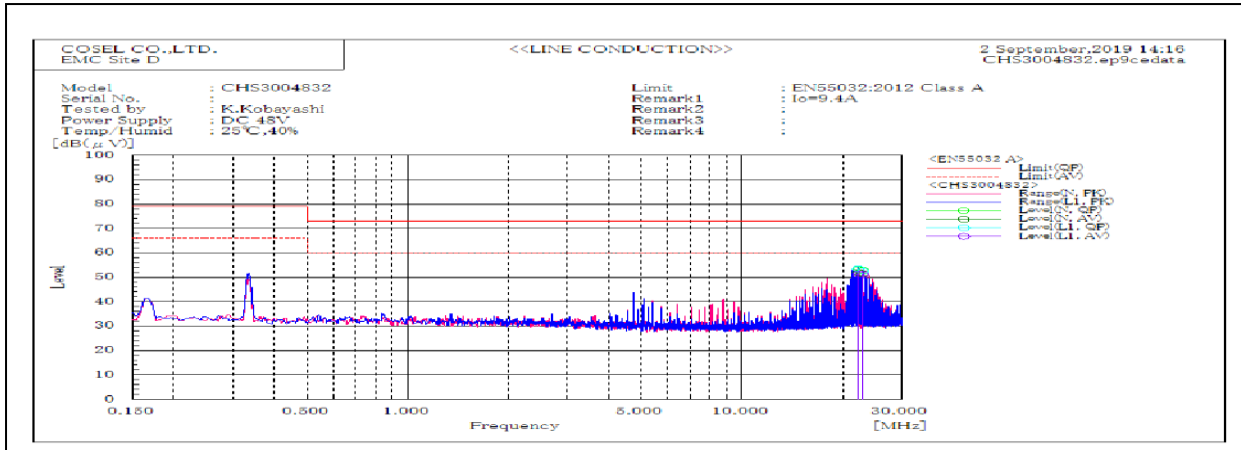
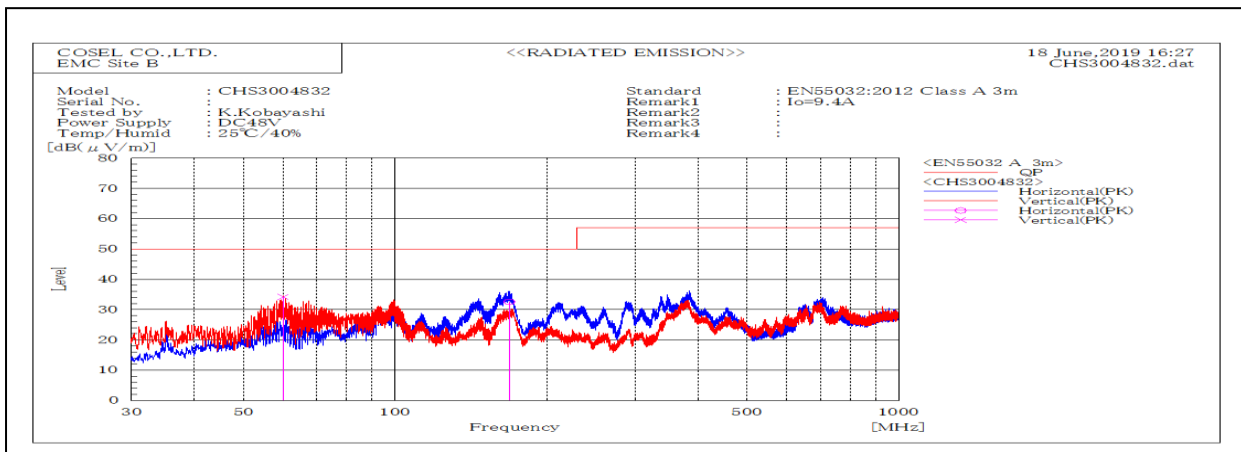


DATA SHEET		Date	02-Sep-19
Model	CHS3004832	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.kobayashi



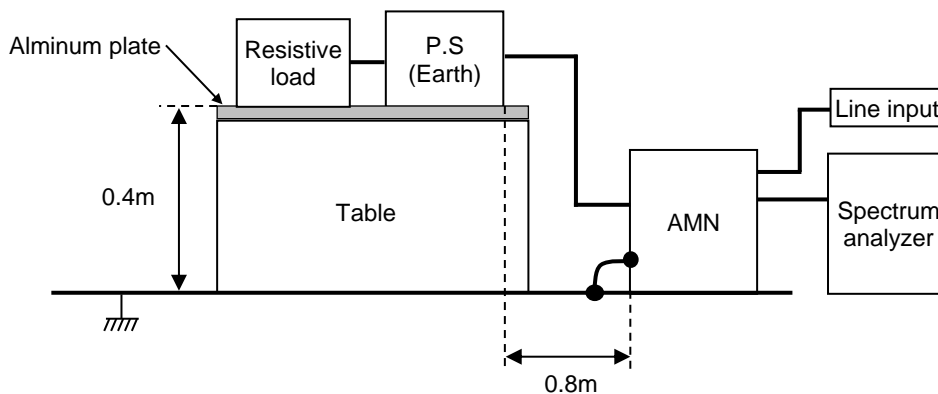
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
		22.27	L1	53.5	51.2	73.0	60.0		
22.94	L1	52.5	51.2	73.0	60.0	20.5	8.8	Pass	
22.27	N	53.2	52.0	73.0	60.0	19.8	8.0	Pass	
22.94	N	52.8	51.6	73.0	60.0	20.2	8.4	Pass	



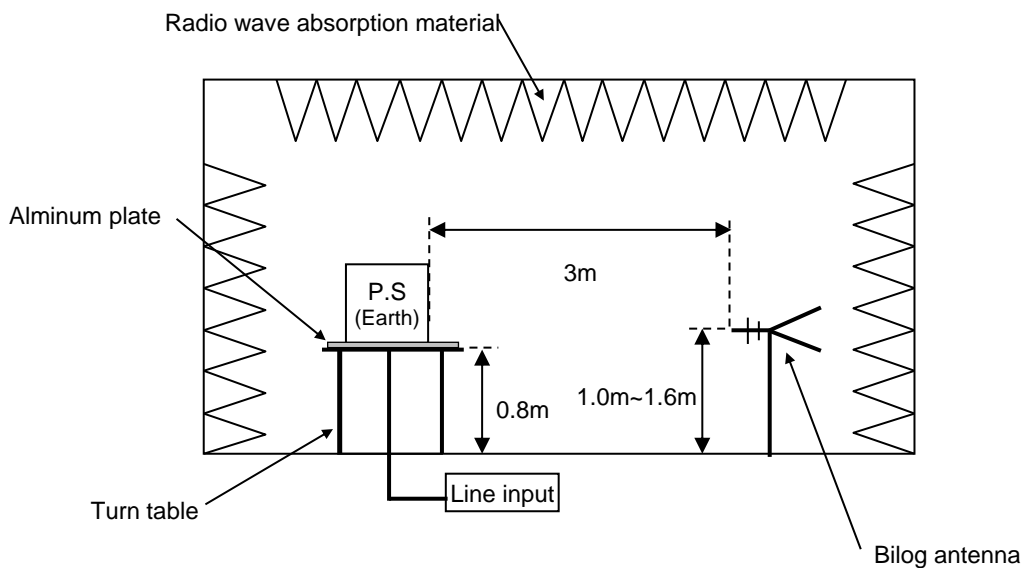
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
168.66	H	Stable	32.5	50.0	17.5	Pass	180.6	129.7	
60.02	V	Stable	34.2	50.0	15.8	Pass	101.4	143.4	

DATA SHEET		Date	02-Sep-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.kobayashi

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
 Model Name : CHS30048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

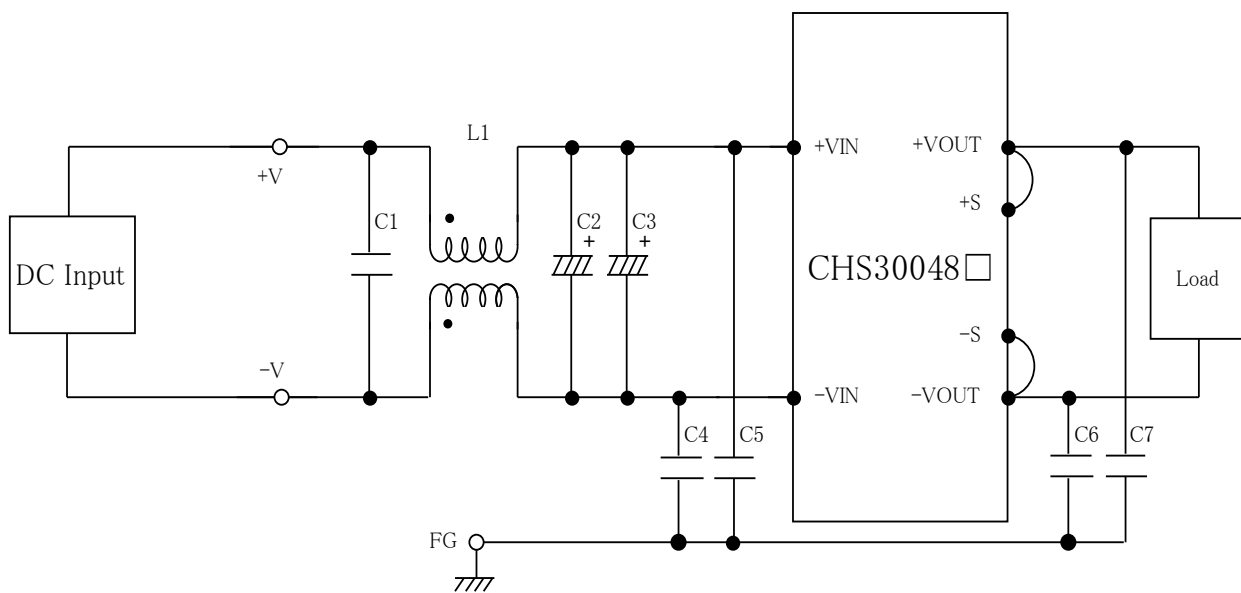


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C3 : 100V 100 μ F PWseries (nichicon)
- C4,C5 : 630V 0.068 μ F FPD22J683J4(NITSUKO)
- C6,C7 : 630V 0.033 μ F FPD22J333J4(NITSUKO)